

Attorney Docket No. 04083/LH

**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Applicant(s): Takashi YONEYAMA, et al.

Serial No. : 10/773,524

Confirm. No.: 7190

Filed : February 6, 2004

For : DEFECT INSPECTION APPARATUS AND
DEFECT INSPECTION METHOD

Art Unit : 2624

Examiner : Tsung Yin Tsai

This paper is being submitted
via EFS-Web on November 17, 2008

In the event that this Paper is
late filed, and the necessary
petition for extension of time
is not filed concurrently
herewith, please consider this
as a Petition for the requisite
extension of time, and to the
extent not already paid,
authorization to charge the
extension fee to Account
No. 06-1378. In addition,
authorization is hereby given to
charge any fees for which
payment has not been submitted,
or to credit any overpayments,
to Account No. 06-1378.

R E S P O N S E

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

This is responsive to the Office Action mailed May 20, 2008,
the term for response to which is extended by three months by
Petition filed concurrently herewith to November 20, 2008.

Remarks begin on page 2 of this paper.